

Search Notes

Application/Control No.

10/706,902

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

CHAE ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	66	1/26/2006	BT
216	72	1/26/2006	BT
216	74	1/26/2006	BT

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search keywords and inventor's name using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	1/26/2006	BT